



TEST REPORT

Report No. A-24-019

Date of Issue: 3 June 2024

Department of Defense Interface Standard Military Standard 461 G

This test report is to certify that the device was tested according to the requirements of the above.
The results of this report should not be construed to imply compliance of devices other than the sample tested. Without the laboratory approval by the documents, this report should not be copied in part.

1. Applicant

Company Name : Panasonic Connect Co., Ltd.
Address : ytv Kyobashi Building, 2-2-33 Shiromi, Chuo-ku, Osaka 540-8553, Japan

2. Identification of Tested Device

Device Name : Personal Computer
Model Number : CF-33
Serial Number : 4DTTC00033
Trade Name : Panasonic
Type of Test : ☐ Product Validation ☒ Design Validation ☐ Development Purpose
Test Plan Number : KEC-G111H A-24-019 2024/4/22
Modification of Test Plan : ☒ No ☐ Yes (refer to deviation information in this report)

3. Test Items

CE101	conducted emissions, audio frequency currents, power leads.	☒ Pass	☐ Fail	☐ N/A
CE102	conducted emissions, radio frequency potential, power leads.	☒ Pass	☐ Fail	☐ N/A
CS101	conducted susceptibility, power leads.	☒ Pass	☐ Fail	☐ N/A
CS114	conducted susceptibility, bulk cable injection.	☒ Pass	☐ Fail	☐ N/A
CS115	conducted susceptibility, bulk cable injection, impulse excitation.	☒ Pass	☐ Fail	☐ N/A
CS116	conducted susceptibility, damped sinusoidal transients, cables and power leads.	☒ Pass	☐ Fail	☐ N/A
CS117	conducted susceptibility, lightning induced transients, cables and power leads.	☐ Pass	☐ Fail	☒ N/A(*3)
CS118	personnel borne electrostatic discharge.	☒ Pass	☐ Fail	☐ N/A
RE101	radiated emissions, magnetic field.	☒ Pass	☐ Fail	☐ N/A
RE102	radiated emissions, electric field.	☒ Pass	☐ Fail	☐ N/A
RS101	radiated susceptibility, magnetic field.	☒ Pass	☐ Fail	☐ N/A
RS103	radiated susceptibility, electric field.	☒ Pass	☐ Fail	☐ N/A

Refer the below reason(s) with respect to the decision and justification not to test.

(*1) DUT Specification (*2) Request of Applicant (*3) According to Test Plan (*4) Not Included in This Report

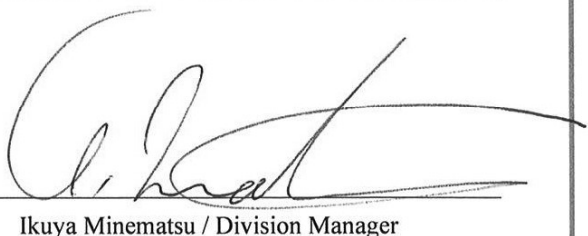
KEC Electronic Industry Development Center Testing Division
3-2-2, Hikari-dai, Seika-cho, Soraku-gun, Kyoto 619-0237 Japan

Test Engineer(s)


Hisanori Sugimoto



Approved by


Ikuya Minematsu / Division Manager